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MEMC 98-3052/2512.2  
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Robert J. Falster

Art Unit 2814

Serial No. 10/038,084

Filed January 3, 2002

Confirmation No. 7363

For SILICON ON INSULATOR STRUCTURE HAVING A LOW DEFECT DENSITY  
DEVICE LAYER AND A PROCESS FOR THE PREPARATION THEREOF

Examiner A. D. Mai

October 24, 2003

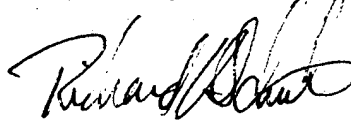
TO THE COMMISSIONER OF PATENTS AND TRADEMARKS,

SIR:

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance  
\* with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit copies of the  
references listed on the attached PTO/SB/08A for consideration by the Patent and  
Trademark Office in the above-entitled application and to be made of record therein.

Respectfully submitted,



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RAS/skd  
\*Enclosures

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<b>PTO/SB/08A</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/038,084
				Filing Date	January 3, 2002
				Confirmation Number	7363
				First Named Inventor	Robert J. Falster
				Group Art Unit	2814
Examiner Name	Anh D. Mai				
Sheet	1	of	1	Attorney Docket No.	MEMC 98-3052/2512.2

U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY		
		Number	Kind Code <sup>2</sup> (if known)				
	121	6,180,220	B1	Falster et al.	01-30-2001		
	122	6,221,743	B1	Fujikawa et al.	04-24-2001		
	123	6,236,104	B1	Falster	05-22-2001		
	124	5,194,395		Wada	03-16-1993		
FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>
		Office	Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)			
OTHER ART - NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.					T <sup>6</sup>
	125	International Search Report for analogous application No. PCT/US02/19906 dated May 8, 2003.					

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached or place an "A" here if English language abstract is attached.

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